

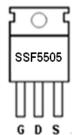
# SSPL5505

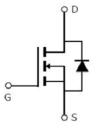
### Main Product Characteristics:

V <sub>DSS</sub>	55V	
R <sub>DS</sub> (on)	4.5mohm(typ.)	
I <sub>D</sub>	160A (1)	



TO220





Marking and pin Assignment

Schematic diagram

#### **Features and Benefits:**

- Advanced Process Technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 175°C operating temperature



## **Description:**

These N-Channel enhancement mode power field effect transistors are produced using silikron proprietary MOSFET technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switch mode power supplies.

## **Absolute max Rating:**

Symbol	Parameter	Max.	Units	
I <sub>D</sub> @ TC = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	160 ①		
I <sub>D</sub> @ TC = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	110 ①	Α	
I <sub>DM</sub>	I <sub>DM</sub> Pulsed Drain Current ②		1	
	Power Dissipation 3	230	W	
P <sub>D</sub> @TC = 25°C	Linear Derating Factor	1.5	W/°C	
V <sub>DS</sub>	Drain-Source Voltage		V	
V <sub>GS</sub> Gate-to-Source Voltage		± 20	V	
E <sub>AS</sub> Single Pulse Avalanche Energy @ L=0.3mH		960	mJ	
I <sub>AS</sub>	Avalanche Current @ L=0.3mH	80	А	
T <sub>J</sub> T <sub>STG</sub>	Operating Junction and Storage Temperature Range	-55 to +175	°C	



# **Thermal Resistance**

Symbol	Characterizes	Тур.	Max.	Units
R <sub>eJC</sub>	Junction-to-case ③	—	0.65	°C/W
В	Junction-to-ambient (t $\leq$ 10s) (4)	—	62	°C/W
R <sub>θJA</sub>	Junction-to-Ambient (PCB mounted, steady-state) ④	_	40	°C/W

## **Electrical Characterizes** $@T_A=25^{\circ}C$ unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source breakdown voltage	55	—	—	V	$V_{GS} = 0V, I_{D} = 250 \mu A$
Р		—	4.5	5	mΩ	V <sub>GS</sub> =10V,I <sub>D</sub> =75A
$R_{DS(on)}$	Static Drain-to-Source on-resistance	—	7.74	—		T <sub>J</sub> = 125℃
Maarin	Gate threshold voltage	2	—	4	v	$V_{DS} = V_{GS}, I_D = 150 \mu A$
$V_{GS(th)}$	Gate meshold voltage	_	2.0	—	v	T <sub>J</sub> = 125℃
I	Drain to Source lookage ourrent		—	1		$V_{DS} = 55V, V_{GS} = 0V$
I <sub>DSS</sub>	Drain-to-Source leakage current		—	50	μA	T <sub>J</sub> = 125℃
	Cata to Source forward lookage	—	—	100	nA	V <sub>GS</sub> =20V
I <sub>GSS</sub> Gate-to-Source forwa	Gate-to-Source forward leakage	-100	—	—		V <sub>GS</sub> = -20V
Qg	Total gate charge	—	101.6	—		I <sub>D</sub> = 75A,
$Q_{gs}$	Gate-to-Source charge	—	25.8	—	nC	V <sub>DS</sub> =30V,
$Q_{gd}$	Gate-to-Drain("Miller") charge	—	40.1	—		$V_{GS} = 10V$
t <sub>d(on)</sub>	Turn-on delay time	—	19.4	—		$V_{GS}$ =10V, $V_{DD}$ =30V,
tr	Rise time	—	88.2	—	nS	$R_L=0.4\Omega$ ,
t <sub>d(off)</sub>	Turn-Off delay time		45.1	_	115	$R_{GEN}=2.7\Omega$
t <sub>f</sub>	Fall time		74.2	_		I <sub>D</sub> =75A
C <sub>iss</sub>	Input capacitance	—	7128	_		$V_{GS} = 0V$
Coss	Output capacitance	—	837	—	pF	V <sub>DS</sub> =50V
C <sub>rss</sub>	Reverse transfer capacitance	_	110	—		f = 1MHz

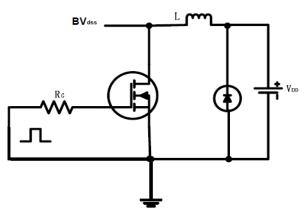
# **Source-Drain Ratings and Characteristics**

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
1	Continuous Source Current			100 @	٨	MOSFET symb
IS	(Body Diode)	— — 160 (1		160 ① A		showing the
I <sub>SM</sub>	Pulsed Source Current	_	_	640	А	integral reverse
	(Body Diode)					p-n junction diode.
V <sub>SD</sub>	Diode Forward Voltage		0.87	1.3	V	$I_{S}$ =75A, $V_{GS}$ =0V, $T_{J}$ = 25°C
t <sub>rr</sub>	Reverse Recovery Time		49.5	_	nS	$T_J$ = 25°C, $I_F$ =75A, di/dt =
Q <sub>rr</sub>	Reverse Recovery Charge		93.8		nC	100A/µs

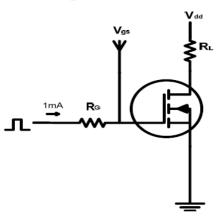


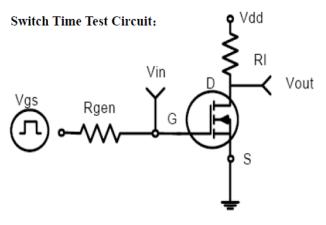
## **Test circuits and Waveforms**

EAS test circuits:

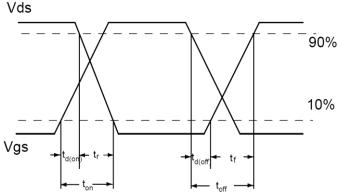


Gate charge test circuit:





Switch Waveforms:



### Notes:

- ①Calculated continuous current based on maximum allowable junction temperature. Package limitation current is 75A
- ②Repetitive rating; pulse width limited by max. junction temperature.
- ③The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- (4) The value of  $R_{\theta JA}$  is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with TA =25°C
- 5 These curves are based on the junction-to-case thermal impedence which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of  $T_{J(MAX)}$ =175°C.



# SSPL5505



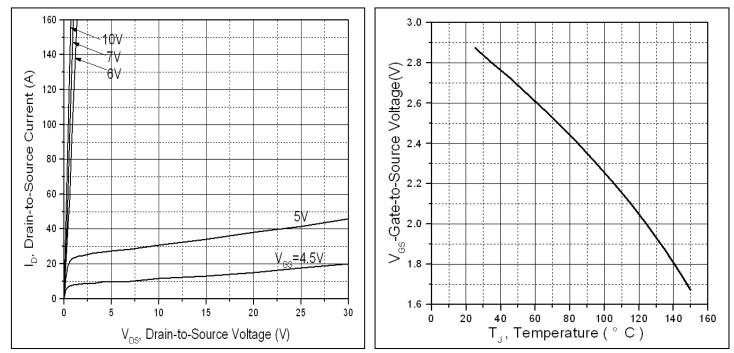


Figure 1: Typical Output Characteristics



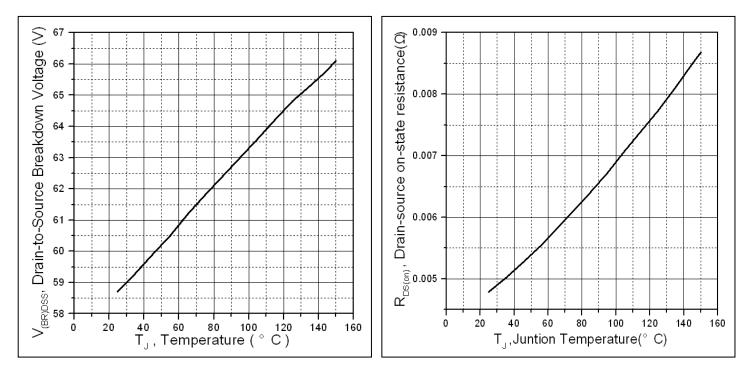
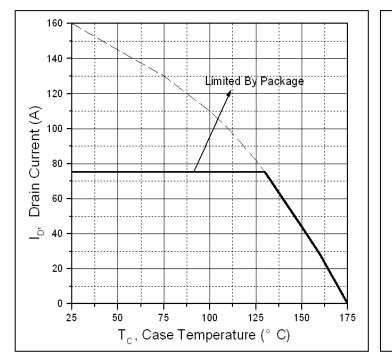


Figure 3. Drain-to-Source Breakdown Voltage vs. Temperature

Figure 4: Normalized On-Resistance Vs. Case Temperature



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# Typical electrical and thermal characteristics



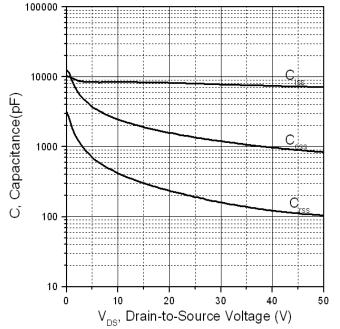


Figure 6.Typical Capacitance Vs. Drain-to-Source Voltage

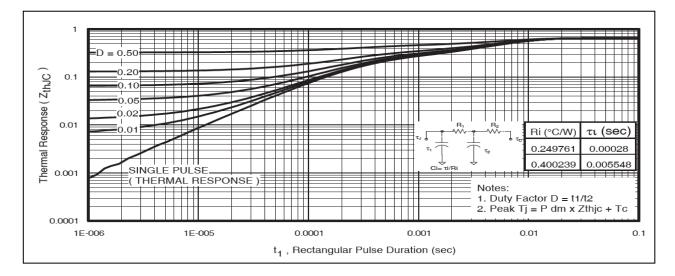
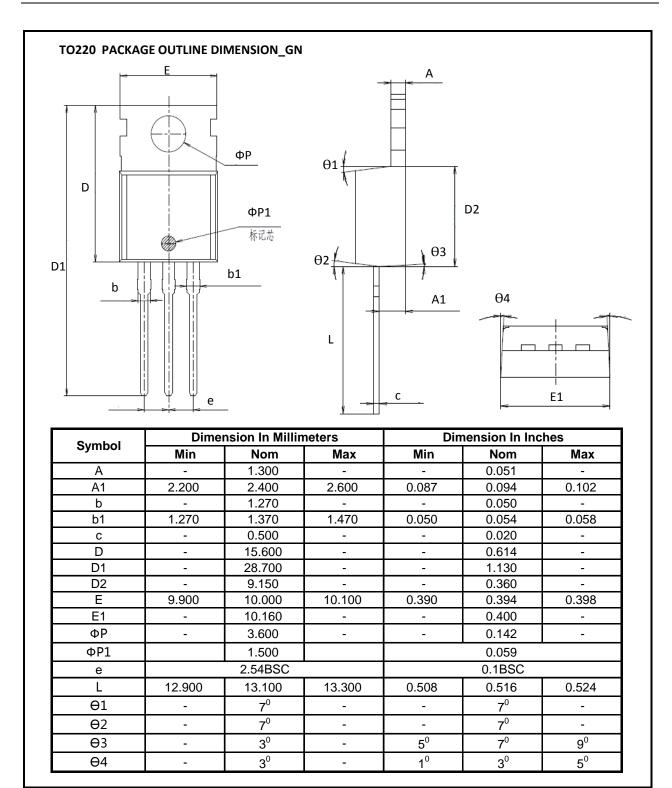


Figure7. Maximum Effective Transient Thermal Impedance, Junction-to-Case







# **Ordering and Marking Information**

Device Marking: SSPL5505	
Package (Available)	
TO220	
Operating Temperature Range	
C : -55 to175 °C	

# **Devices per Unit**

Package Type	Units/ Tube	Tubes/Inner Box	Units/Inner Box	Inner Boxes/Carton Box	Units/Carton Box
TO220	50	20	1000	6	6000

# **Reliability Test Program**

Test Item	Conditions	Duration	Sample Size
High	T <sub>j</sub> =125℃ to 175℃ @	168 hours	3 lots x 77 devices
Temperature	80% of Max	500 hours	
Reverse	V <sub>DSS</sub> /V <sub>CES</sub> /VR	1000 hours	
Bias(HTRB)			
High	T <sub>j</sub> =125℃ or 175℃ @	168 hours	3 lots x 77 devices
Temperature	100% of Max V <sub>GSS</sub>	500 hours	
Gate		1000 hours	
Bias(HTGB)			



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#### Worldwide Sales and Service:

Sales@silikron.com

#### **Technical Support:**

Technical@silikron.com

#### Suzhou Silikron Semiconductor Corp.

11A, 428 Xinglong Street, Suzhou Industrial Park, P.R.China

**TEL:** (86-512) 62560688

FAX: (86-512) 65160705

E-mail: Sales@silikron.com